

Notice of Allowability

Application No.

10/810,645

Applicant(s)

KER ET AL.

Examiner

Art Unit

Jeff Natalini

2858

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

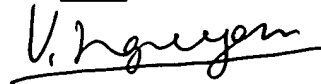
1. ☒ This communication is responsive to amendment filed 8/23/06.
2. ☒ The allowed claim(s) is/are 1-35.
3. ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some* c) ☐ None of the:
1. ☐ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. _____.
3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).
- * Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

4. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
5. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
- (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
- 1) ☐ hereto or 2) ☐ to Paper No./Mail Date _____.
- (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date _____.
- Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
6. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

1. ☐ Notice of References Cited (PTO-892)
2. ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/08), Paper No./Mail Date _____
4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material
5. ☐ Notice of Informal Patent Application (PTO-152)
6. ☐ Interview Summary (PTO-413), Paper No./Mail Date _____
7. ☒ Examiner's Amendment/Comment
8. ☐ Examiner's Statement of Reasons for Allowance
9. ☐ Other _____



VINCENT Q. NGUYEN
PRIMARY EXAMINER

DETAILED ACTION

EXAMINER'S AMENDMENT

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it **MUST** be submitted no later than the payment of the issue fee.

Claims 1 and 18 will be amended as follows (any added words are underlined, and deleted words are crossed out):

In claim 1, on line 10 "second" is changed to "third"; on line 11 "and second" is added after "provided to the first"; finally, the "and" from line 13 is moved up to line 12.

In claim 18, in line 11, "second point" is changed to "third point"

Claim 1:

A system for measuring electrostatic discharge (ESD) characteristics of a semiconductor device, comprising:

- at least one pulse generator generating ESD-scale pulses;
- a first point of the semiconductor device receiving a first ESD-scale pulse from the at least one pulse generator;
- a second point of the semiconductor device receiving the first ESD-scale pulse from the at least one pulse generator;
- at least a third point of the semiconductor device receiving a second ESD-scale pulse from the at least one pulse generator, wherein the second ESD-scale pulse is provided to the ~~second~~ third point of the semiconductor device approximately at the same time as the first ESD-scale pulse is provided to the first and second point of the semiconductor device; and
- a data collector to collect data on the ESD characteristics of the semiconductor device.

Art Unit: 2858

Claim 18:

A method of measuring electrostatic discharge (ESD) characteristics of a semiconductor device, comprising:

- providing at least one pulse generator generating ESD-scale signals;
 - identifying a first point on the semiconductor device;
 - identifying a second point on the semiconductor device;
 - identifying a third point on the semiconductor device;
 - providing a first ESD-scale signal to the first and second points of the semiconductor device; and
 - providing a second ESD-scale signal to at least the third point on the semiconductor device,
- wherein the second ESD-scale signal is provided to the ~~second~~ third point of the semiconductor device approximately at the same time as the first ESD-scale signal is provided to the first point and the second point of the semiconductor device.

Authorization for this examiner's amendment was given in a telephone interview with Mr. Clark Jablon on September 8, 2006.

Allowable Subject Matter

Claims 1-35 are allowed.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jeff Natalini whose telephone number is 571-272-2266. The examiner can normally be reached on M-F 8-5.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Andrew Hirshfeld can be reached on 571-272-2168. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Jeff Natalini

A handwritten signature in black ink, appearing to be 'JN' or 'Jeff Natalini', located below the printed name.

REPLACEMENT SHEET
for Application No. 10/810,645

*Approved
9/8/06
gm*

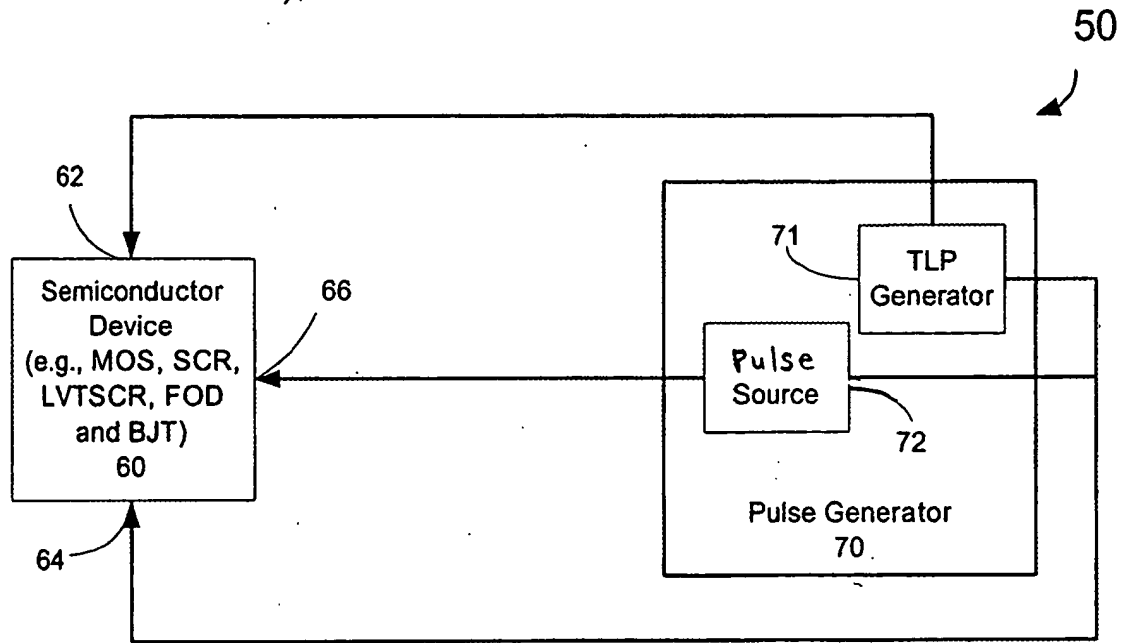


FIG. 5

REPLACEMENT SHEET
for Application No. 10/810,645

Approved
9/8/06
Jm

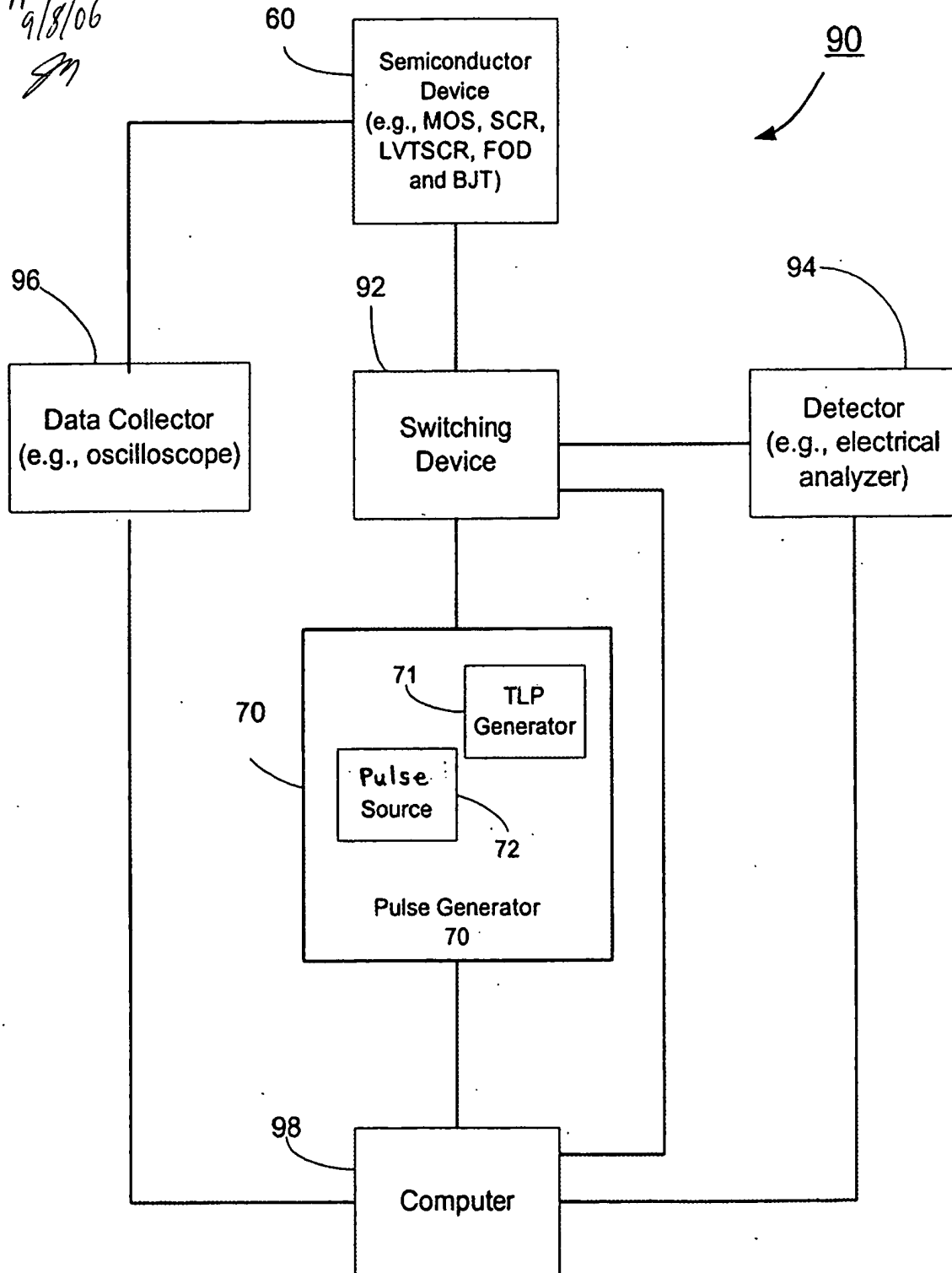


FIG. 6